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National Standards Authority of Ireland

IRISH STANDARD

I.S. EN 60749-1:2003

ICS 31.080.01

National Standards
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SEMICONDUCTOR DEVICES - MECHANICAL AND CLIMATIC TEST METHODS

PART 1: GENERAL

(IEC 60749-1:2002)

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EUROPEAN STANDARD **EN 60749-1**

NORME EUROPÉENNE

EUROPÄISCHE NORM June 2003

ICS 31.080.01

Supersedes EN 60749:1999 + A1:2000 + A2:2001

English version

Semiconductor devices - Mechanical and climatic test methods Part 1: General

(IEC 60749-1:2002)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques Partie 1: Généralités (CEI 60749-1:2002)

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren Teil 1: Allgemeines (IEC 60749-1:2002)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 47/1638/FDIS, future edition 1 of IEC 60749-1, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-1 on 2002-09-24.

This European Standard, together with the other parts of the series EN 60749, supersedes EN 60749:1999 + A1:2000 + A2:2001, in which the test methods were contained in one standard which was subdivided into chapters relating to mechanical test methods, climatic test methods and miscellaneous test methods.

The following dates were fixed:

– latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2004-01-01

– latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2005-10-01

Each test method governed by this standard and which is part of the series is a stand-alone document, numbered EN 60749-2, EN 60749-3, etc. The numbering of these test methods is sequential, and there is no relationship between the number and the test method (i.e. no grouping of test methods). The list of these tests will be available in the CENELEC internet site and in the catalogue.

Updating of any of the individual test methods is independent of any other part.

Annexes designated "normative" are part of the body of the standard.
In this standard, annex ZA is normative.
Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60749-1:2002 was approved by CENELEC as a European Standard without any modification.

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Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

Publication	Year	Title	EN/HD	Year
IEC 60050	Series	International Electrotechnical Vocabulary (IEV)	-	-
IEC 60747	Series	Semiconductor devices - Discrete devices	EN 60747	Series
IEC 60748	Series	Semiconductor devices - Integrated circuits	-	-

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Partie 1: Généralités

Semiconductor devices – Mechanical and climatic test methods –

Part 1: General

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